

Multi-element SDD fluorescence X-ray detector system

MADE IN JAPAN

High-count rate, High-sensitive by multielement and DSP processing

SYSTEM

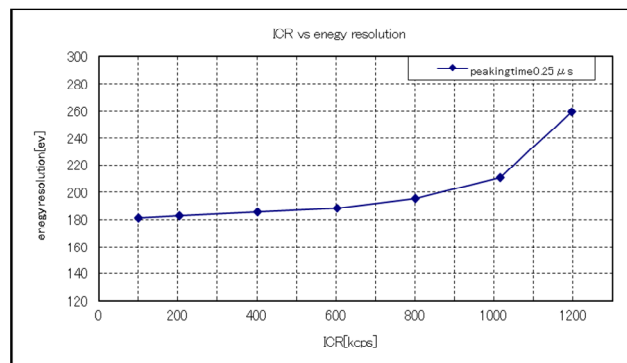
XSSD50 Series is all-in-one system which has detector, which is needed X-ray absorption microstructure measurement in the analysis of materials field, data acquisition board, and power supply. It was realized high-sensitivity by multiple SDD detector with high-count rate and energy resolution. Additionally, it is possible to be measured high-count rate by a transistor reset processing and DSP processing.

(e.g.: 7 element SDD detector)

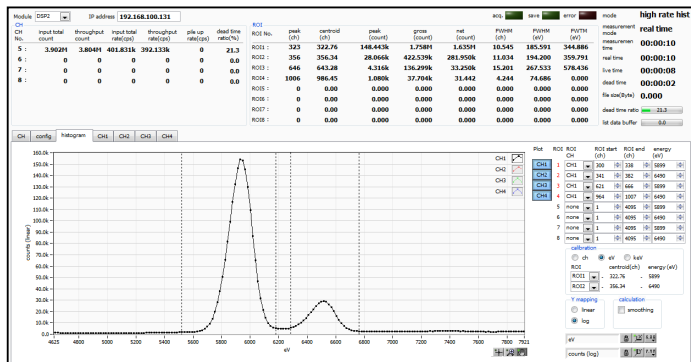


Right: 100MADC,
Left: SDD for power supply

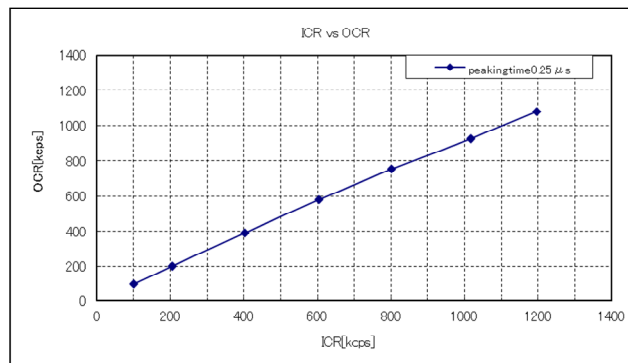
- All element area : 455mm² (65mm² × 7 element)
- All effective area : 350mm²
(collimated to 50mm² × 7 element)
- Function : Histogram, List, Waveform, ROI-SCA
- ADC : 8CH 100MSPS 14bit
- Energy resolution : 244eV@5.9keV MnK α
(Peakingtime 0.25μs, 1000kOCR)
- Power supply for SDD : -200V, ±5V, +3.3V
- Interface : Ethernet (TCP/IP)
- Accessory : Application, Instruction manual



ICR vs Energy resolution



400k ICR 185eV@5.9keV 0.25μs Peakingtime
Application



ICR vs OCR

※ Please note that contents may change without prior notice.

Techno AP

Design and fabrication of electronic circuit associated with measurement control and radiation measurement

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